## **AMENDMENTS TO THE CLAIMS:**

## Listing of claims:

This listing of claims replaces all prior versions and listings of claims in the application.

Claim 1 (Currently Amended): A test apparatus used for evaluating testing a multilayer wiring board formed by successively being fabricated by stacking wiring layers successively, said test apparatus comprising:

a prove part configured to be connected to an incomplete probe that detects defects in the multilayer wiring board that is in a half finished state before completion under fabrication; and a supplementary part supplementing an element of an element supplementing unit that mounts additional elements on the multilayer wiring board, said incomplete multilayer wiring board lacking said element under fabrication when no defect is detected by the probe.

Claim 2 (Currently Amended): The test apparatus as claimed in claim 1, wherein the supplementary part includes layer wiring of the multilayer wiring board, said incomplete multilayer wiring board lacking said layer wiring additional elements to be mounted are included in the element supplementing unit.

Claim 3 (New): The test apparatus as claimed in claim 1, wherein the element supplementing unit includes

a first section arranged to face a first side of the multilayer wiring board under fabrication to mount the additional elements on the first side; and

a second section arranged to face a second side of the multilayer wiring board under fabrication to mount the additional elements on the second side.

Claim 4 (New): A method of fabricating a multilayer wiring board, comprising:

a first step of testing the multilayer wiring board under fabrication to detect whether defects exist;

a second step of mounting additional elements on the multilayer wiring board under fabrication when no defect is detected;

a third step of testing the multilayer wiring board including the additionally mounted elements; and

a fourth step of continuing or stopping mounting of further additional elements according to testing results of the third step.

Claim 5 (New): The method as claimed in claim 4, wherein a test apparatus is provided to test the multilayer wiring board under fabrication and to mount the additional elements, said test apparatus comprising a probe for testing and an element supplementing unit for mounting the additional elements.

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Claim 6 (New): The method as claimed in claim 5, wherein the additional elements to be mounted are carried by the element supplementing unit.

Claim 7 (New): The method as claimed in claim 4, wherein testing and mounting of the additional elements are performed on opposite two sides of the multilayer wiring board under fabrication.